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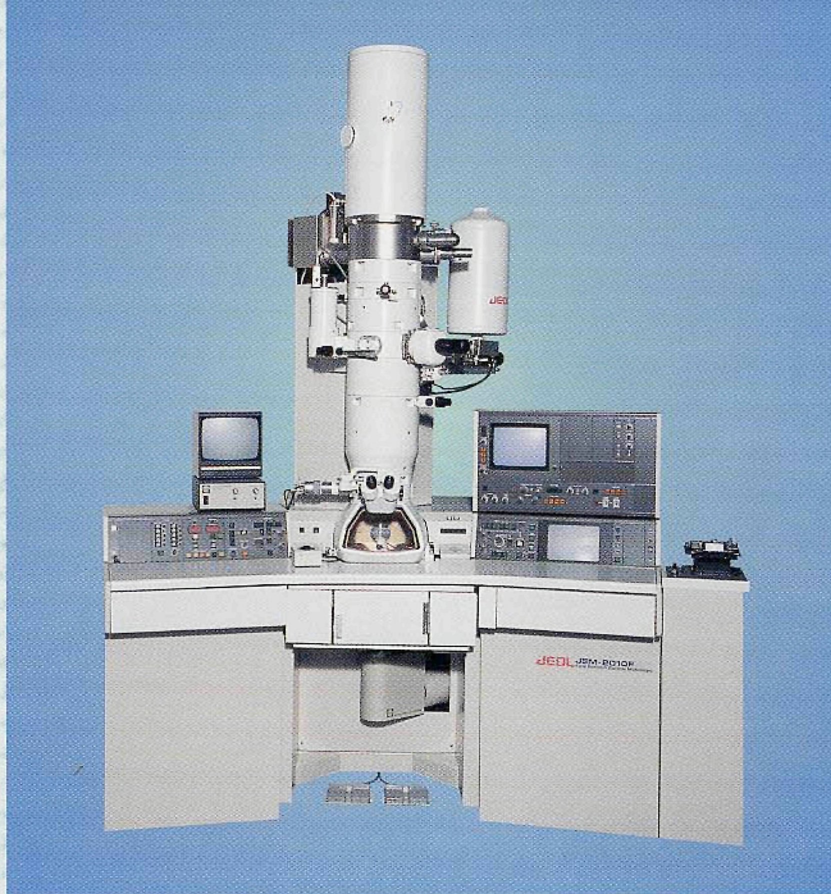

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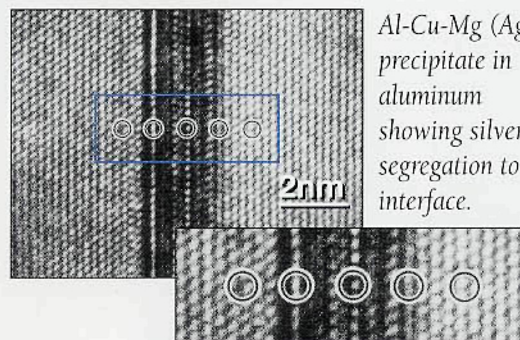
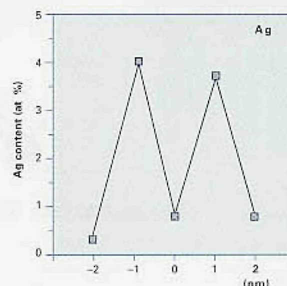


Al-Cu-Mg (Ag) precipitate in aluminum showing silver segregation to interface.



Data courtesy of Dr. James M. Howe, Department of Materials Science & Engineering, University of Virginia, U.S.A.

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Lumina™ is the first and only integrated microscope that lets you see your sample across the complete optical spectrum and beyond. Use the conventional inverted optical microscope to find the area of interest of your sample. Then switch to Lumina's near-field (NSOM) mode and view the exact same area, but in the 50nm resolution range. Since both modes employ the same optics, you can use the same filters, beam splitters, and detectors. Now, for even more information, change to the AFM scanning mode and get high-resolution topographic and surface-force data about your sample. And do all of this, everything, with one integrated instrument.

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Far-field

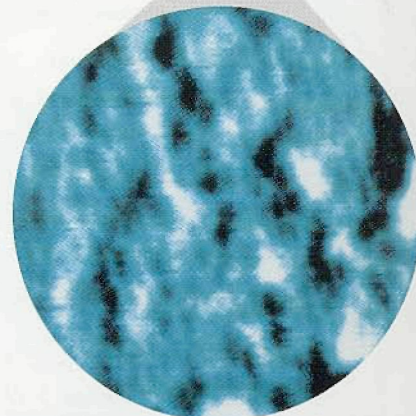
A phase-contrast image of polytene chromosomes obtained with the inverted optical microscope.

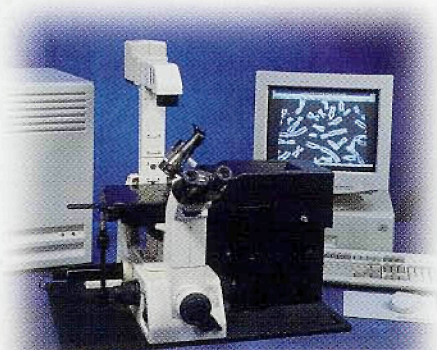
AFM

An atomic force image of the circled area in the inverted optical microscope view shows surface topography over a 30µm area.

Near-field

An 8µm, NSOM transmission image magnifies the circled area of the AFM image, showing more transmitted light in the brighter areas.





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